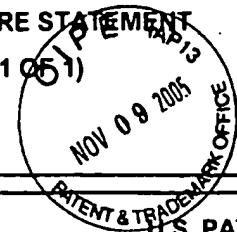


INFORMATION DISCLOSURE STATEMENT PTO-1449 (PAGE 1 OF 1)		SERIAL NUMBER 10/791,830	DOCKET NO. P57015
		APPLICANT HYUN-KI PARK, et al.	
		FILING DATE 4 March 2004	GROUP 1753



U.S. PATENT DOCUMENTS						
EXAMINER	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
FOREIGN PATENT DOCUMENTS						TRANSLATION
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	YES
LV	KR 2000-0016858	03/00	Republic of Korea			Abstract
LV	KR 1999-0060730	07/99	Republic of Korea			Abstract
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)						
LV	Office Action from the Korean Intellectual Property Office issued in Applicant's corresponding Korean Patent Application No. 10-2003-0026391 dated 18 August 2005.					
EXAMINER:	<i>Leah Van</i>		DATE CONSIDERED:	12/6/05		

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP §609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

INFORMATION DISCLOSURE STATEMENT PTO-1449 (PAGE 1 OF 1)	SERIAL NUMBER 10/791,830	DOCKET NO. P57015
APPLICANT: HYUN-KI PARK et al.		
FILING DATE: 4 March 2004		GROUP NO.

U.S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

TRANSLATION

FOREIGN PATENT DOCUMENTS						REFERENCE	
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLAS	YES	NO
LV	EP0963146	12/8/99	Great Britain			Abstract	
LV	JP2000261187	9/22/00	Japan			Abstract	
LV	JP56166059	12/19/81	Japan			Abstract	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

L V Van den Bulcke, E. European Search Report, dated 16 June 2004.

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INFORMATION DISCLOSURE STATEMENT PTO-1449 (PAGE 1 OF 1)	SERIAL NUMBER	DOCKET NO. P57015
	APPLICANT	HYUN-KI PARK
	FILING DATE 4 March 2004	GROUP

U.S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

TRANSLATION

FOREIGN PATENT DOCUMENTS					SEARCHED		
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	YES	NO
LV	JP11-167350	6/99	Japan			Abstract	
LV	JP2002-062814	2/02	Japan			Abstract	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER: *Mark Van* **DATE CONSIDERED:** *12/6/05*

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